

# Young Bong Shin

## List of Publications by Year in descending order

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17  
papers

129  
citations

1307594

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h-index

1281871

11  
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docs citations

17  
times ranked

97  
citing authors

| #  | ARTICLE   | IF  | CITATIONS |
|----|---|-----|-----------|
| 1  | Influence of passivation layer on thermal stability of Nb:TiO <sub>2</sub> samples for shutter-less infrared image sensors. Infrared Physics and Technology, 2019, 100, 52-56.          | 2.9 | 3         |
| 2  | Anodic Aluminum Oxide-Based IR Emitter for High-Speed Infrared Scene Projector. Journal of Microelectromechanical Systems, 2019, 28, 1032-1038.   | 2.5 | 7         |
| 3  | Residual stress analysis of anodic aluminum oxide thin films for infrared emitter device application.. , 2019, , .  |     | 1         |
| 4  | Enhanced bolometric properties of nickel oxide thin films for infrared image sensor applications by substitutional incorporation of Li. Ceramics International, 2018, 44, 7808-7813.    | 4.8 | 4         |
| 5  | Influence of Nb Doping Concentration on Bolometric Properties of RF Magnetron Sputtered Nb:TiO <sub>2</sub> Films. Journal of Electronic Materials, 2018, 47, 2171-2176.                | 2.2 | 2         |
| 6  | Improvement of the thermal stability of Nb:TiO <sub>2</sub> samples for uncooled infrared detectors. Journal Physics D: Applied Physics, 2018, 51, 025104.                              | 2.8 | 5         |
| 7  | Bolometric properties of oxygen atmosphere annealed Nb:TiO <sub>2</sub> films for infrared detectors. Ceramics International, 2017, 43, 9207-9213.                                      | 4.8 | 5         |
| 8  | Sputtering pressure dependent bolometric properties of Ni <sub>1-x</sub> O thin films for uncooled bolometer applications. Ceramics International, 2017, 43, 9498-9504.                 | 4.8 | 4         |
| 9  | Effect of sputtering pressure on microstructure and bolometric properties of Nb:TiO <sub>2</sub> films for infrared image sensor applications. Journal of Applied Physics, 2016, 119, . | 2.5 | 12        |
| 10 | Nb doping effect on TiO <sub>2</sub> films for bolometer applications. Journal of Physics and Chemistry of Solids, 2016, 91, 128-135.   | 4.0 | 9         |
| 11 | Substrate temperature dependent bolometric properties of TiO <sub>2</sub> films for infrared image sensor applications. Ceramics International, 2016, 42, 17123-17127.                  | 4.8 | 14        |
| 12 | Influence of deposition temperature on TiO <sub>2</sub> films for infrared image sensor applications: TiO <sub>2</sub> films: Infrared image sensor applications. , 2015, , .           |     | 0         |
| 13 | Bolometric properties of reactively sputtered TiO <sub>2</sub> films for thermal infrared image sensors. Journal Physics D: Applied Physics, 2015, 48, 355104.                          | 2.8 | 18        |
| 14 | Oxygen partial pressure and thermal annealing dependent properties of RF magnetron sputtered TiO <sub>2</sub> films. Materials Science in Semiconductor Processing, 2015, 32, 107-116.  | 4.0 | 20        |
| 15 | Enhanced bolometric properties of TiO <sub>2</sub> thin films by thermal annealing. Applied Physics Letters, 2015, 107, .   | 3.3 | 18        |
| 16 | Systematic Investigation on Deposition Temperature Effect of Ni <sub>1-x</sub> O Thin Films for Uncooled Infrared Image Sensor Applications. IEEE Sensors Journal, 2015, 15, 7234-7241. | 4.7 | 7         |
| 17 | Oxygen Atmosphere Annealing Effect on the Thermal Stability of TiO <sub>2</sub> -Based Films for Shutter-Less Infrared Image Sensors. Key Engineering Materials, 0, 775, 272-277.       | 0.4 | 0         |